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Docket Number: 061063-0316598

PATENT APPLICATION

Client Reference: OSP-18418

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re the Application of

JEA GUN PARK, et al.

Group Art Unit: 2812

Application No.: 10/540,992

Examiner: Unassigned

Filed: June 5, 2006

Confirmation No.: 9014

For: CHEMICAL-MECHANICAL-POLISHING SLURRY COMPOSITION, METHOD FOR PLANARIZING SURFACE OF SEMICONDUCTOR DEVICE USING THE SAME, AND METHOD FOR CONTROLLING SELECTION RATIO OF SLURRY COMPOSITION

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR 1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Copies of cited U.S. patents and patent application publications are not included. Copies of foreign patent documents and non-patent literature are included. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom. Applicants respectfully request the Examiner return an initialed copy of the enclosed Form PTO-1449 to Applicants with the next Office communication to indicate that the references has been considered, per MPEP § 609.

This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of the first Office Action on the merits in the present application. No certification or fee is required.

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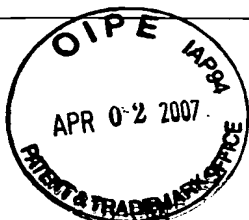
The references were cited in a counterpart foreign application. An English language version of the foreign search report is attached for the Examiner's information.

Respectfully Submitted,
PILLSBURY WINTHROP SHAW PITTMAN LLP



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To: Atty. Dkt. No. M# Client Ref.
061063 0316598 OSP-18418

**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**

Applicant: Jea Gun PARK et al.

Appln. No.: 10/540,992

Filing Date: June 5, 2006

Examiner: Unassigned Group Art Unit: 2812

Date: April 2, 2007

Page 1 of 1

U.S. PATENT DOCUMENTS

| Examiner's Initials* | Document Number | Date MM/YYYY | Name (Family Name of First Inventor) | Class | Sub Class | Filing Date (if appropriate) |
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| YR | J.Y. KIM et al., "Effect of Crystallinity of Ceria Particles on the PETEOS Removal Rate in Chemical Mechanical Polishing for Shallow Trench Isolation", Journal of the Korean Physical Society, vol. 41, No. 4, October 2002, pps. 413-416. | | | X |
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Examiner Date Considered:

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.